

Static IR Drop Prediction with Limited Data from Real Designs

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Outline

- ML for IR-drop prediction
- Our methodology
- Simulation results
- Conclusion

ML for IR-drop prediction: Introduction

- Static IR drop analysis of power delivery network (PDN) is a crucial task in IC design
 - Voltage drop is induced between the power pads and cells in the design
 - High IR drops can severely impact the normal functionality of chips
- Traditional techniques require solving a system of equations representing KVL and KCL and can take up to few hours using commercial tools

ML for IR-drop prediction: prior work

- Earlier work for PDN analysis trade off accuracy for speed by utilizing techniques like spatial locality [DAC'11], preconditioned conjugate gradient [ICCAD'11].
- Recently, machine learning (ML)-based techniques provide significantly faster and more accurate solutions
 - Limited to incremental analysis [VTS'18, VLSID'22]
 - Applicable to specific designs [ASPDAC'20]
 - Not accurate enough [ASPDAC'21]

ML for IR-drop prediction: challenges

1. Complexity of PDNs

- 3D network with up to 10 layers
- Hard to make accurate predictions
- 2. Lack data from real chips for AI-based prediction
 - Large amounts of training data are often required to produce accurate predictions

Methodology: overview

- Translate the original problem to image-to-image prediction
- Train our model using the two-step pretrain-finetune strategy
- Make prediction and evaluate







- The Power delivery networks can be modeled as a 3D grid of voltage sources, current sources, and resistances
 - Wires are a network of resistances, the power pad (C4 bumps) are voltages sources connected to the PDN wires, and the current sources are the cells/instances



- PDN features can be represented by images
 - Current map shows locations of current sources
 - PDN density map reflects the topology of a PDN
 - Effective distance to power pads shows the location of power pads
 - Resistance maps represent resistances of all metal layers/vias
- IR drops across a chip can be represented by an IR drop map

Resizing

– Since the chip dimensions may be different, we apply resizing to adjust all image-based inputs to the same dimension (512×512) to allow processing by the same NN model

Normalization

 For better adaptability, each input image is scaled to [0, 1] by dividing by its maximum matrix entry

Methodology : AttUNet architecture



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Methodology : AttUNet architecture



Proposed AttUNet which is an advanced U-Net-based CNN

- U-Net CNN: encoder-decoder structure, which is commonly used for image-to-image prediction tasks [MICCAI' 15]
- Highlighted parts are new

Methodology : AttUNet architecture

1) PreConv Block:

- A convolutional layer inserted to preprocess the inputs which has a 2
 × 2 filter and an activatior function ReLU for *each* image-based input
- Works as a quick filter to highlight the salient features of each imagebased input



 Allows subsequent convolution operations to work with more relevant and distinguishing features, and better handle the multi-image to single-image nature of the prediction problem

Methodology: AttUNet architecture

2) Attention gates:

- Added to the skipping connections between each pair of encoder and decoders
- Selectively emphasizes relevant features in the sparse IR drop maps
- Reduces noise and improves model accuracy



Methodology: data augment & model training



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Methodology: data augment

Data augmentation:

- We augment the training data by applying multiple transformations to each imagebased input
 - For each input given operations are applied: vertical and horizontal flipping and three (counter-clockwise) rotations
- This process results in a sixfold increase in the number of testcases





Methodology: model training



Model training:

- Transfer learning strategy
 - · First pretrain using large volume of artificially-generated data to prevent overfitting
 - Then finetune using limited data from real designs
- The provided dataset in the ICCAD 2023 contest contains 120 test cases in total for training, of which 100 are artificially-generated and the remaining 20 are real
- Each test case is represented as 12 image-based inputs and is also accompanied by an image-based golden output IR drop map

Methodology: model training

Model training:

- Pretrain
 - High learning rate and dropout _____ rate to facilitate robust learning
- Finetuning
 - Cosine annealing learning rate: Balances exploration in the parameter space with precise tuning
- Custom loss function
 - Ensures conservative estimates of IR drop by penalizing underestimated values, aiming for safer design outcomes



Simulation results: Hyperparameters

Model hyperparameters	PreConv	filter size	2×2		
		# filters	12		
	C1	filter size	3×3		
	U1	# filters	32		
	C2	filter size	3×3		
	U2	# filters	64		
	C3	filter size	3×3		
	U3	# filters	128		
	C4	filter size	3×3		
	U4	# filters	256		
	Bottleneck	filter size	3×3		
		# filters	512		
Training parameters		Pre-train	Fine-tune		
	Epochs	450	600		
	Optimizer	ADAM	ADAM		
	Learning rate	0.005	0.00001-0.001		
	Dropout	0.3-0.5	0.15		

Codes are available on https://github.com/lzzh97/Static-IR-Drop-Prediction

Simulation results: prediction quality

- The prediction quality was evaluated using the same metrics from the ICCAD 2023 contest
 - Mean Absolute Error (MAE) : reflects an overall prediction accuracy
 - Absolute error between predicted IR drop and the ground-truth

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$$MAE = \frac{\sum_{i=0}^{N} |\widehat{V_i} - V_i|}{N}$$

- F1 Score: reflects prediction accuracy in high drop pixels
 - The highest 10% IR drops are labeled as positive and the rest as negative
 - $F1 = \frac{2 \times precision \cdot recall}{precision + recall}$

• Besides metrics used in the contest, we also define a third metric to reflect the MAE in the very high IR drop regions

 $-MAE_H$: MAE in top 5% IR drop regions

Simulation results: prediction quality

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 Compared AttUNet against: 		IREDGe			ConvNeXtV2 (Contest Winner)			AttUNet		
– ICCAD'23 contest winner		MAE	F1	MAE_H	MAE	F1	MAE_H	MAE	F1	MAE_H
from NTU	T7	0.124	0.648	0.182	0.066	0.783	N/A	0.057	0.656	0.120
– IREDGe: U-Net based	T8	0.110	0.698	0.159	0.082	0.816	N/A	0.067	0.791	0.113
model	T9	0.205	0.120	0.307	0.041	0.589	N/A	0.074	0.562	0.111
[Chhabria et al, ASPDAC'21]*	T10	0.141	0.483	0.255	0.066	0.532	N/A	0.089	0.610	0.122
 Attl INIot significantly 		0.119	0.417	0.193	0.207	0.000	N/A	0.164	0.590	0.220
Automet Significantiy	T14	0.192	0.034	0.244	0.422	0.000	N/A	0.089	0.734	0.230
outperforms both models		0.157	0.000	0.286	0.097	0.088	N/A	0.077	0.234	0.150
 Improves accuracy and in 	T16	1.066	0.000	1.431	0.160	0.529	N/A	0.096	0.614	0.150
predicting IR drop	T19	0.131	0.037	0.250	0.091	0.501	N/A	0.085	0.283	0.044
hotspots	T20	0.089	0.000	0.187	0.118	0.711	N/A	0.035	0.723	0.050
	Ave.	0.233	0.244	0.349	0.135	0.455	N/A	0.084	0.580	0.131

* V. A. Chhabria, V. Ahuja, A. Prabhu, P. Nikhil, P. Jain, S. S. Sapatnekar. "Thermal and IR Drop Analysis Using Convolutional Encoder-Decoder Networks". ASP-DAC., pp. 690-696. 2021.

Conclusions

- We presented AttUnet, an advanced variant of the U-Net architecture enhanced with attention mechanisms to predict static IR drop in power delivery networks
- Our findings demonstrated that AttUNet significantly surpasses the existing U-Net model and the2023 ICCAD contest winner in prediction quality.
- Our evaluation was using the setup and data provided by the ICCAD 2023 contest, and our code was released on GitHub

Thank you for your attention!

Reference

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